

**Search Notes**

Application/Control No.

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Examiner

Jeffrey R. Snay

Applicant(s)/Patent under  
Reexamination

QUIRK ET AL.

Art Unit

1743

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
prior search updated	6/11/2005	JRS